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Surface Ferromagnetism of CeO₂ Nanoparticles

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Pure CeO₂ nanoparticles were synthesized by water-in-oil microemulsion method. The ceria precursor and the precipitants were Ce(NO₃)₃·6H₂O and NH₄OH, respectively. X-ray diffraction and Raman spectroscopy reveal that the as-prepared CeO₂ nanoparticles are in a fluorite structure without impurity phases and the grain size is 6nm obtained by the full width at half maximum (FWFM) of a diffraction peak. Ferromagnetism (FM) was observed in as-prepared samples at room temperature with the saturation magnetism (Ms) of 5 memu/g. The mild reduction treatments with 1.5% H2 in Ar were performed on the as-prepared samples between 200 °C and 600 °C with incremental steps of 50 °C. For each step, the as-prepared samples were

kept for 1 h at the temperature before cooling to room temperature to measure the magnetism. Magnetic results show a relationship between the Ms and the reduction temperature, as shown in Fig.1. The Ms reaches a maximum (65 memu/g) for the reduction at 350 °C, which is close to the value of as-prepared CeO2 nanoneedles (80 memu/g) reported by Y Liu et al [1], and then decreases with increasing the reduction temperature. It was reported by C. Binet et al [2] that the reduction is limited to the surface for reduction temperatures in the 200-600°C range, and $Ce^{3+}-Ce^{4+}$ pair defects reach a maximum in their surface concentration for a temperature in this range. Based on above results and the charge-transfer model proposed recently by Coev et al [3] for the FM of defective oxide nanoparticles, we suggest that the FM of the CeO₂ nanoparticles arises from the double exchange interaction through charge transfer between the surface mixed valent $Ce^{3+} Ce^{4+}$ pair via O^{2-} ion.

REFERENCES

Y. Liu et al., J. Phys.: Condens. Matter 20, 165201 (2008).
C. Binet et al., J. Phys. Chem. 98, 6392 (1994).
J.M.D. Coey et al., J. Phys. D: Appl. Phys. 41, 134012 (2008).



Fig. 1. Saturation magnetization (Ms) as a function of the reduction temperature (1 h at each temperature).

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The Study of Annealing Effect on Co Implanted ZnO Epitaxial Films

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The Co-ZnO epitaxial thin film was successfully growth grown on Al₂O₃ substrates by ion beam sputtering deposition and 100 KV cobalt ion implantation in the ZnO thin film. The Co-doped ZnO thin film was annealing in a vacuum environment at 600, 700 and 800 degree C using RTA after implantation. The crystal structure was measured by x-ray diffraction (XRD) and local environment of the Co was investigated by x-ray absorption spectroscopy (XAS). The XRD pattern shows typical wurzite structure of the Co-doped ZnO. The magnetization of the Co-doped ZnO was measured by SQUID. The resistance of the Co-doped ZnO shows different characterizations of samples with annealed and without annealed. For instance, the Co-doped ZnO shows a cobalt cluster effect before annealed. After annealing process, the resistance that was increase as a function as the temperature increase to relate to spontaneity magnetic properity was measured. The XAS result of Co also shows a cobalt-oxide-like-structure in the Co-doped ZnO after annealed. An intristic DMSs were grown by controlling the annealing process and the implanted sample has a good chacterication for the applications to of spintronics.

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REFERENCES

J. M. D. Coey et al., Nature Mater., 4, 174 (2005).
H. J. Lee et al., Appl. Phys. Lett., 81, 4020(2002).
J. C. A. Huang et al., Appl. Phys. Lett., 85, 3815(2004).